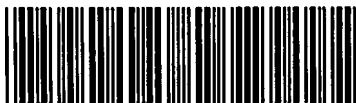


**Search Notes**

Application/Control No.

10/630,789

Examiner

Syed Zaidi

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2609

**SEARCHED**

Class	Subclass	Date	Examiner
370	241	5/21/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in databases: uspat,us-pgpub,epo, jpo, ibm_tdb (see search strategy)	5/21/2007	SZ
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